# **Octal D Flip-Flop**

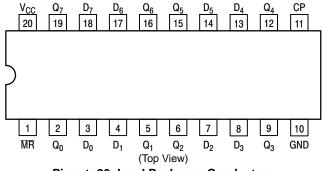
The MC74AC273/74ACT273 has eight edge-triggered D-type flip-flops with individual D inputs and Q outputs. The common buffered Clock (CP) and Master Reset ( $\overline{MR}$ ) inputs load and reset (clear) all flip-flops simultaneously.

The register is fully edge-triggered. The state of each D input, one setup time before the LOW–to–HIGH clock transition, is transferred to the corresponding flip–flop's Q output.

All outputs will be forced LOW independently of Clock or Data inputs by a LOW voltage level on the  $\overline{MR}$  input. The device is useful for applications where the true output only is required and the Clock and Master Reset are common to all storage elements.

## Features

- Ideal Buffer for MOS Microprocessor or Memory
- Eight Edge-Triggered D Flip-Flops
- Buffered Common Clock
- Buffered, Asynchronous Master Reset
- See MC74AC377 for Clock Enable Version
- See MC74AC373 for Transparent Latch Version
- See MC74AC374 for 3-State Version
- Outputs Source/Sink 24 mA
- 'ACT273 Has TTL Compatible Inputs
- These are Pb–Free Devices



**Pinout: 20–Lead Packages Conductors** 

#### MODE SELECT-FUNCTION TABLE

Operating Made		Inputs	Outputs	
Operating Mode	MR	СР	Dn	Qn
Reset (Clear)	L	Х	Х	L
Load '1'	н	Г	Н	Н
Load '0'	Н	Г	L	L

H = HIGH Voltage Level

L = LOW Voltage Level

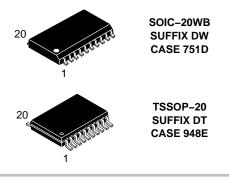
X = Immaterial

\_ = LOW-to-HIGH Clock Transition



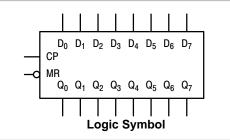
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**PIN ASSIGNMENT** 

PIN	FUNCTION
D <sub>0</sub> -D <sub>7</sub>	Data Inputs
MR	Master Reset
СР	Clock Pulse Input
Q <sub>0</sub> –Q <sub>7</sub>	Data Outputs

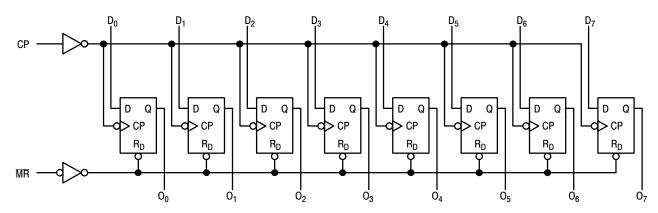


## **ORDERING INFORMATION**

See detailed ordering and shipping information in the package dimensions section on page 6 of this data sheet.

## **DEVICE MARKING INFORMATION**

See general marking information in the device marking section on page 6 of this data sheet.



NOTE: That this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

## Figure 1. Logic Diagram

## MAXIMUM RATINGS

Symbol		Parameter	Value	Unit
V <sub>CC</sub>	DC Supply Voltage (Referenced to	GND)	-0.5 to +7.0	V
V <sub>IN</sub>	DC Input Voltage (Referenced to G	–0.5 to V <sub>CC</sub> +0.5	V	
V <sub>OUT</sub>	DC Output Voltage (Referenced to	GND) (Note 1)	–0.5 to V <sub>CC</sub> +0.5	V
I <sub>IK</sub>	DC Input Diode Current		±20	mA
I <sub>OK</sub>	DC Output Diode Current		±50	mA
I <sub>OUT</sub>	DC Output Sink/Source Current		±50	mA
I <sub>CC</sub>	DC Supply Current, per Output Pin		±50	mA
I <sub>GND</sub>	DC Ground Current, per Output Pin	±100	mA	
T <sub>STG</sub>	Storage Temperature Range	-65 to +150	°C	
ΤL	Lead temperature, 1 mm from Case	for 10 Seconds	260	°C
TJ	Junction Temperature Under Bias		140	°C
$\theta_{JA}$	Thermal Resistance (Note 2)	SOIC TSSOP	65.8 110.7	°C/W
MSL	Moisture Sensitivity	SOIC TSSOP	Level 3 Level 1	
F <sub>R</sub>	Flammability Rating	Oxygen Index: 30% – 35%	UL 94 V–0 @ 0.125 in	
V <sub>ESD</sub>	ESD Withstand Voltage	Human Body Model (Note 3) Machine Model (Note 4) Charged Device Model (Note 5)	> 2000 > 200 > 1000	V
I <sub>Latchup</sub>	Latchup Performance	Above $V_{CC}$ and Below GND at 85°C (Note 6)	±100	mA

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. I<sub>OUT</sub> absolute maximum rating must be observed.

The package thermal impedance is calculated in accordance with JESD 51–7.
 Tested to EIA/JESD22–A114–A.

4. Tested to EIA/JESD22-A115-A.

5. Tested to JESD22-C101-A.

6. Tested to EIA/JESD78.

#### **RECOMMENDED OPERATING CONDITIONS**

Symbol	Parameter		Min	Тур	Max	Unit
M	Supply Veltage	′AC	2.0	5.0	6.0	v
V <sub>CC</sub>	Supply Voltage	'ACT	4.5	5.0	5.5	V
V <sub>in</sub> , V <sub>out</sub>	DC Input Voltage, Output Voltage (Ref. to GND)		0	-	V <sub>CC</sub>	V
			-	150	-	
t <sub>r</sub> , t <sub>f</sub>	t <sub>p</sub> t <sub>f</sub> f AC Devices except Schmitt Inputs	V <sub>CC</sub> @ 4.5 V	-	40	-	ns/V
		V <sub>CC</sub> @ 5.5 V	-	25	-	
	Input Rise and Fall Time (Note 8)	V <sub>CC</sub> @ 4.5 V	-	10	-	
t <sub>r</sub> , t <sub>f</sub>	'ACT Devices except Schmitt Inputs	V <sub>CC</sub> @ 5.5 V	-	8.0	-	ns/V
T <sub>A</sub>	Operating Ambient Temperature Range		-40	25	85	°C
I <sub>OH</sub>	Output Current – High		-	-	-24	mA
I <sub>OL</sub>	Output Current – Low		-	-	24	mA

Functional operation above the stresses listed in the Recommended Operating Ranges is not implied. Extended exposure to stresses beyond the Recommended Operating Ranges limits may affect device reliability. 7.  $V_{IN}$  from 30% to 70%  $V_{CC}$ ; see individual Data Sheets for devices that differ from the typical input rise and fall times. 8.  $V_{IN}$  from 0.8 V to 2.0 V; see individual Data Sheets for devices that differ from the typical input rise and fall times.

## **DC CHARACTERISTICS**

		74AC		74AC			
Symbol	Parameter	V <sub>CC</sub>	T <sub>A</sub> = -	⊦25°C	T <sub>A</sub> = −40°C to +85°C	Unit	Conditions
		(V)	Тур	Gu	aranteed Limits		
V <sub>IH</sub>	Minimum High Level Input Voltage	3.0 4.5 5.5	1.5 2.25 2.75	2.1 3.15 3.85	2.1 3.15 3.85	V	$V_{OUT} = 0.1 V$ or $V_{CC} - 0.1 V$
V <sub>IL</sub>	Maximum Low Level Input Voltage	3.0 4.5 5.5	1.5 2.25 2.75	0.9 1.35 1.65	0.9 1.35 1.65	V	$\begin{array}{l} V_{OUT}=0.1 \ V \\ or \ V_{CC}-0.1 \ V \end{array}$
V <sub>OH</sub>	Minimum High Level Output Voltage	3.0 4.5 5.5	2.99 4.49 5.49	2.9 4.4 5.4	2.9 4.4 5.4	V	I <sub>OUT</sub> = -50 μA
		3.0 4.5 5.5		2.56 3.86 4.86	2.46 3.76 4.76	V	$^{*}V_{IN} = V_{IL} \text{ or } V_{IH}$ -12 mA $I_{OH}$ -24 mA -24 mA
V <sub>OL</sub>	Maximum Low Level Output Voltage	3.0 4.5 5.5	0.002 0.001 0.001	0.1 0.1 0.1	0.1 0.1 0.1	V	I <sub>OUT</sub> = 50 μA
		3.0 4.5 5.5	_ _ _	0.36 0.36 0.36	0.44 0.44 0.44	V	$V_{IN} = V_{IL} \text{ or } V_{IH}$ $12 \text{ mA}$ $I_{OL}$ $24 \text{ mA}$ $24 \text{ mA}$
I <sub>IN</sub>	Maximum Input Leakage Current	5.5	-	±0.1	±1.0	μA	$V_I = V_{CC}, GND$
I <sub>OLD</sub> I <sub>OHD</sub>	†Minimum Dynamic Output Current	5.5 5.5	-	-	75 –75	mA	V <sub>OLD</sub> = 1.65 V Max V <sub>OHD</sub> = 3.85 V Min
Icc	Maximum Quiescent Supply Current	5.5	-	8.0	80	μA	$V_{IN} = V_{CC}$ or GND

\*All outputs loaded; thresholds on input associated with output under test. †Maximum test duration 2.0 ms, one output loaded at a time.

NOTE: Note:  $I_{IN}$  and  $I_{CC}$  @ 3.0 V are guaranteed to be less than or equal to the respective limit @ 5.5 V V<sub>CC</sub>.

AC CHARACTERISTICS (For Figures and Waveforms - See Section 3 of the ON Semiconductor FACT Data Book, DL138/D)

				74AC		74	AC		
Symbol	Parameter	V <sub>CC</sub> * (V)	T <sub>A</sub> = +	25°C C <sub>L</sub> =	50 pF	$T_A = -40^{\circ}C$ to +8	85°C C <sub>L</sub> = 50 pF	Unit	Figure No.
		(•)	Min	Тур	Max	Min	Max		110.
f <sub>max</sub>	Maximum Clock Frequency	3.3 5.0	90 140	125 175		75 125		Mhz	3–3
t <sub>PLH</sub>	Propagation Delay Clock to Output	3.3 5.0	4.0 3.0	7.0 5.5	12.5 9.0	3.0 2.5	14.0 10.0	ns	3–6
t <sub>PHL</sub>	Propagation Delay Clock to Output	3.3 5.0	4.0 3.0	7.0 5.0	13.0 10.0	3.5 2.5	14.5 11.0	ns	3–6
t <sub>PHL</sub>	Propagation Delay MR to Output	3.3 5.0	4.0 3.0	7.0 5.0	13.0 10.0	3.5 2.5	14.0 10.5	ns	3–6

\*Voltage Range 3.3 V is 3.3 V  $\pm$ 0.3 V. Voltage Range 5.0 V is 5.0 V  $\pm$ 0.5 V.

### AC OPERATING REQUIREMENTS

			74	AC	74AC		
Symbol	Parameter	V <sub>CC</sub> * (V)	T <sub>A</sub> = +25°C	C <sub>L</sub> = 50 pF	$T_A = -40^{\circ}C$ to +85°C $C_L = 50$ pF	Unit	Figure No.
		(.,	Тур		Guaranteed Minimum		
ts	Setup Time, HIGH or LOW Data to CP	3.3 5.0	3.5 2.5	5.5 4.0	6.0 4.5	ns	3–9
t <sub>h</sub>	Hold Time, HIGH or LOW Data to CP	3.3 5.0	-2.0 -1.0	0 1.0	0 1.0	ns	3–9
t <sub>w</sub>	Clock Pulse Width HIGH or LOW	3.3 5.0	3.5 2.5	5.5 4.0	6.0 4.5	ns	3–6
t <sub>w</sub>	MR Pulse Width HIGH or LOW	3.3 5.0	2.0 1.5	5.5 4.0	6.0 4.5	ns	3–6
t <sub>rec</sub>	Recovery Time MR to CP	3.3 5.0	1.5 1.0	3.5 2.0	4.5 3.0	ns	3–9

\*Voltage Range 3.3 V is 3.3 V  $\pm$ 0.3 V. Voltage Range 5.0 V is 5.0 V  $\pm$ 0.5 V.

## DC CHARACTERISTICS

			744	СТ	74ACT		
Symbol	Parameter	V <sub>CC</sub> (V)	T <sub>A</sub> = -	+25°C	T <sub>A</sub> = –40°C to +85°C	Unit	Conditions
			Тур	Gua	ranteed Limits		
V <sub>IH</sub>	Minimum High Level Input Voltage	4.5 5.5	1.5 1.5	2.0 2.0	2.0 2.0	V	$V_{OUT} = 0.1 V$ or $V_{CC} - 0.1 V$
V <sub>IL</sub>	Maximum Low Level Input Voltage	4.5 5.5	1.5 1.5	0.8 0.8	0.8 0.8	V	$V_{OUT} = 0.1 V$ or $V_{CC} - 0.1 V$
V <sub>OH</sub>	Minimum High Level Output Voltage	4.5 5.5	4.49 5.49	4.4 5.4	4.4 5.4	V	I <sub>OUT</sub> = -50 μA
		4.5 5.5		3.86 4.86	3.76 4.76	V	$^{*}V_{IN} = V_{IL} \text{ or } V_{IH}$ $I_{OH} -24 \text{ mA}$ -24  mA
V <sub>OL</sub>	Maximum Low Level Output Voltage	4.5 5.5	0.001 0.001	0.1 0.1	0.1 0.1	V	I <sub>OUT</sub> = 50 μA
		4.5 5.5		0.36 0.36	0.44 0.44	V	*V <sub>IN</sub> = V <sub>IL</sub> or V <sub>IH</sub> 24 mA I <sub>OL</sub> 24 mA
I <sub>IN</sub>	Maximum Input Leakage Current	5.5	-	±0.1	±1.0	μΑ	$V_I = V_{CC}, GND$
$\Delta I_{CCT}$	Additional Max. I <sub>CC</sub> /Input	5.5	0.6	-	1.5	mA	$V_{I} = V_{CC} - 2.1 V$
I <sub>OLD</sub> I <sub>OHD</sub>	†Minimum Dynamic Output Current	5.5 5.5			75 –75	mA	V <sub>OLD</sub> = 1.65 V Max V <sub>OHD</sub> = 3.85 V Min
I <sub>CC</sub>	Maximum Quiescent Supply Current	5.5	-	8.0	80	μΑ	$V_{IN} = V_{CC}$ or GND

\*All outputs loaded; thresholds on input associated with output under test.

†Maximum test duration 2.0 ms, one output loaded at a time.

## AC CHARACTERISTICS (For Figures and Waveforms – See Section 3 of the ON Semiconductor FACT Data Book, DL138/D)

				74ACT		74 <i>A</i>	74ACT		
Symbol Parameter		V <sub>CC</sub> * (V)	T <sub>A</sub> = +25°C C <sub>L</sub> = 50 pF			$T_A = -40^{\circ}C \text{ to } +85^{\circ}C$ $C_L = 50 \text{ pF}$		Unit	Figure No.
			Min	Тур	Max	Min	Max		
f <sub>max</sub>	Maximum Clock Frequency	5.0	125	200	-	125	-	MHz	3–3
t <sub>PHL</sub>	Propagation Delay Clock to Output	5.0	3.0	6.0	10	2.5	11.0	ns	3–6
t <sub>PLH</sub>	Propagation Delay Clock to Output	5.0	3.0	6.5	11	2.5	12.0	ns	3–6
t <sub>PHL</sub>	Propagation Delay MR to Output	5.0	3.0	7.0	11	2.5	11.5	ns	3–6

\*Voltage Range 5.0 V is 5.0 V ±0.5 V.

## AC OPERATING REQUIREMENTS

			74A	СТ	74ACT		
Symbol Parameter		V <sub>CC</sub> * (V)	T <sub>A</sub> = +25°C C <sub>L</sub> = 50 pF		T <sub>A</sub> = -40°C to +85°C C <sub>L</sub> = 50 pF	Unit	Figure No.
			Typ Guarar		Inteed Minimum		
ts	Setup Time, HIGH or LOW – Data to CP	5.0	3.0	4.5	5.0	ns	3–9
t <sub>h</sub>	Hold Time, HIGH or LOW – Data to CP	5.0	-2.5	2.0	2.0	ns	3–9
tw	Clock Pulse Width – HIGH or LOW	5.0	2.5	4.0	4.5	ns	3–6
t <sub>w</sub>	MR Pulse Width – HIGH or LOW	5.0	2.5	4.0	4.5	ns	3–6
t <sub>rec</sub>	Recovery Time – MR to CP	5.0	-1.0	2.0	3.0	ns	3–6

\*Voltage Range 5.0 V is 5.0 V  $\pm$ 0.5 V.

## CAPACITANCE

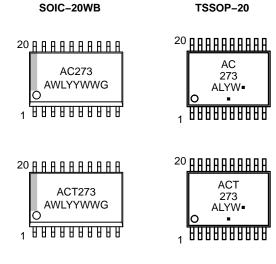
Symbol	Parameter	Value Typ	Unit	Test Conditions
C <sub>IN</sub>	Input Capacitance	4.5	pF	$V_{CC} = 5.0 V$
C <sub>PD</sub>	Power Dissipation Capacitance	50	pF	$V_{CC} = 5.0 V$

## **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
MC74AC273DWG	SOIC-20WB (Pb-Free)	38 Units / Rail
MC74AC273DWR2G	SOIC-20WB (Pb-Free)	1000 / Tape & Reel
MC74AC273DTR2G	TSSOP-20 (Pb-Free)	2500 / Tape & Reel
MC74ACT273DWG	SOIC–20WB (Pb–Free)	38 Units / Rail
MC74ACT273DWR2G	SOIC-20WB (Pb-Free)	1000 / Tape & Reel
MC74ACT273DTR2G	TSSOP-20 (Pb-Free)	2500 / Tape & Reel

+For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

## MARKING DIAGRAMS

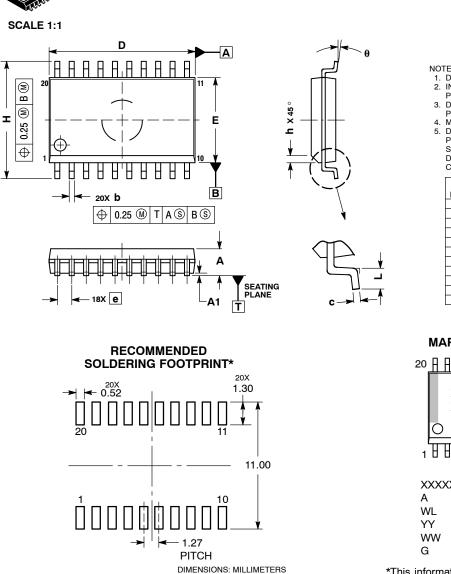


A =	Assembly	Location
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- WL, L = Wafer Lot
- YY, Y = Year
- WW, W = Work Week

G or = = Pb-Free Package

(Note: Microdot may be in either location)



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

DATE 22 APR 2015

DUSEM

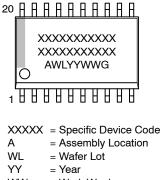
NOTES:

SOIC-20 WB CASE 751D-05 ISSUE H

- 1. DIMENSIONS ARE IN MILLIMETERS. 2. INTERPRET DIMENSIONS AND TOLERANCES
- PER ASME Y14.5M, 1994. 3. DIMENSIONS D AND E DO NOT INCLUDE MOLD PROTRUSION. MAXIMUM MOLD PROTRUSION 0.15 PER SIDE.
- DIMENSION B DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE PROTRUSION SHALL BE 0.13 TOTAL IN EXCESS OF B DIMENSION AT MAXIMUM MATERIAL CONDITION.

	MILLIMETERS		
DIM	MIN	MAX	
Α	2.35	2.65	
A1	0.10	0.25	
b	0.35	0.49	
C	0.23	0.32	
D	12.65	12.95	
Е	7.40	7.60	
е	1.27 BSC		
Н	10.05	10.55	
h	0.25	0.75	
L	0.50	0.90	
θ	0 °	7 °	

GENERIC **MARKING DIAGRAM\*** 



= Work Week = Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking. Pb–Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

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